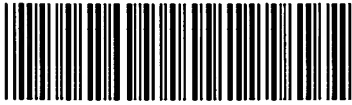


Search Notes

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10/614,080

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

NAKASHIMA, ATSUHISA

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
updated	updated	3/8/2005	<i>mm</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
347	32,104	3/8/2005	<i>mm</i> SWH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR